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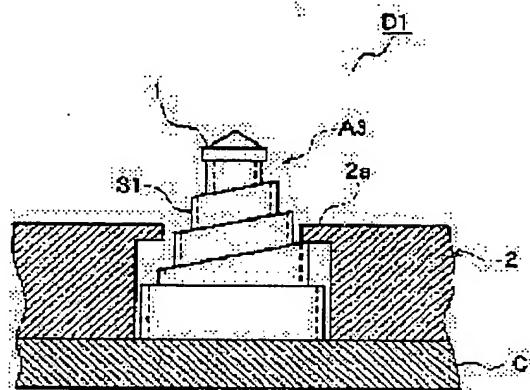
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(21)Application number : 2000-043644 (71)Applicant : SEIKEN CO LTD
 (22)Date of filing : 21.02.2000 (72)Inventor : SHIRATORI NOBUO

(54) INSPECTION PROBE AND INSPECTION DEVICE WITH INSPECTION PROBE

(57)Abstract:

PROBLEM TO BE SOLVED: To reduce the attenuation of a high-frequency electric signal when the electric signal is detected.
 SOLUTION: When the probe part 1 of an inspection probe A3 is brought into contact with the terminal (not indicated in the figure) of a component to be inspected, the probe part 1 is brought surely into contact by the urging force of a spring part S1. As the spring part S1, a spiral spring part whose coil diameter becomes gradually small toward the inner circumferential side from the outer circumferential side is used, and its total length can be made short as compared with a spring part whose coil diameter is uniform. As a result, even when the high-frequency electric signal is detected, the attenuation of the electric signal can be reduced.



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